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| Substitute Form PTO-1449 (Modified) | U.S. Department of Commerce Patent and Trademark Office | Attorney's Docket No. 13906-196001 | Application No. 10/816,909 |
| Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b)) | | Applicant Marcus Dill, et al. | |
| | | Filing Date April 5, 2004 | Group Art Unit 2181 |

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| Examiner Initial | Desig. ID | Document Number | Publication Date | Country or Patent Office | Class | Subclass | Translation | |
| | AL | | | | | | Yes | No |
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| Examiner Signature /Leon Harper/ | Date Considered 06/22/2008 |
| EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. | |